Search Notes

Application/Control	No.

Applicant(s)/Patent under Reexamination
HATOH ET AL.

10/397,811 Examiner

Art Unit

Julian Mercado

1745

SEARCHED					
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Updated Search (Atalul)	48/26		
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